EV318279717

Inventor: Jon P. Daley

inventor: , bon i . Baro,

Title:

Methods of Forming Patterned Photoresist Layers Over

Semiconductor Substrates

Assignee: Micron Technology, Inc.

INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR § 1.56. Copies of the cited art are included. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 9-5-03

Mark S. Matkin Reg. No. 32,268

Form PTO-1449 . U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2380

SERIAL NO. Unknown

LIST OF ART CITED BY ARRIVANT

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					FILING DATE Filed Herewith			OUP nown	
U.S. PATEN	IT DOC	UMENTS	-						
*Examiner's Initials		Document Number	Date	Name		Class	Subclass Filing Date If Appropriate		
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